

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SCHILZ ET AL.	
		Examiner Richard Bueker	Art Unit 1763	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,550,257	10-1985	Binnig et al.	250/492.2
	C	US-5,147,823	09-1992	Ishibashi et al.	438/694
	D	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ulke, Microelectronic Engineering 53 (2000) 261-264
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.